

**Search Notes**

Application/Control No.

10/510,704

Examiner

John S. Chu

Applicant(s)/Patent under  
Reexamination

HATANAKA ET AL.

Art Unit

1752

**SEARCHED**

Class	Subclass	Date	Examiner
430	191	6/2005	jrc
430	192		
430	193		
430	165		
430	326		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH in file	6/2005	jrc
Inventor search in EAST		